Electrostatic Discharge (ESD) Testing Report

Applicant Department: MingXin Microelectronics Corporation LTD	
Product: MX3085E	Case NO: S121127006
Test Item: System-Level ESD Testing	Package/Pin Count: SOP8
Application Date: 11/27/2012	Date Finished: 11/27/2012
Test Method: IEC 61000-4-2(150pF/ 330ohm)&(100pF/ 1500ohm)	
Test Equipment: EM TEST / ESD P30C	Temperature: 25℃±5℃ Humidity: 55%±10%RH
Failure Criteria: Device no longer meets the parts drawing requirements using V+I envelope around REFERENCE I-V curve (pre-zap). (Current tolerance ± 30%, Voltage tolerance ± 30%)	
Test Voltage: (±)8KV,(±)15KV;	

ESD GUN TESTING Result

MODEL: ESD GUN		ESD SENSITIVITY PASS: +/-15000V	
TEST MODE ZAP VOLTAGE		SAMPLE SIZE	PASSED VOLTS
Contact Discharge (Zap +/-8000V)	Condition 1* 150pF/ 330ohm	3(#7,#8,#9)	+/-8000V
Air Discharg (Zap +/-15000V)		3(#10,#11,#12)	+/-15000V
Contact Discharge (Zap +/-8000V)	Condition 2* 150pF/ 330ohm	3(#13,#14,#15)	+/-8000V
Air Discharg (Zap +/-15000V)		3(#16,#17,#18)	+/-15000V
Contact Discharge (Zap +/-8000V)	Condition 3* 150pF/ 330ohm	3(#19,#20,#21)	+/-8000V
Air Discharg (Zap +/-15000V)		3(#22,#23,#24)	+/-15000V
Contact Discharge (Zap +/-8000V)	Condition 4* 150pF/ 330ohm	3(#25,#26,#27)	+/-8000V
Air Discharg (Zap +/-15000V)		3(#28,#29,#30)	+/-15000V
Contact Discharge (Zap +/-15000V)	Condition 5* 100pF/ 1500ohm	3(#38,#39,#40)	+/-15000V

Electrostatic Discharge (ESD) Testing Report

Applicant/Department:MingXin Microelectronics Corporation LTD	
Product:MX3085E	Case NO: S121127006
Test Item: Human Body Model (HBM)	Package/Pin Count: SOP8
Application Date: 11/27/2012	Date Finished: 11/27/2012
Test Method: MIL-STD-883H Method 3015.8	Zap: 3 pulse, Interval: 1.0 S
Test Equipment: Thermo Keytek Zapmaster7/4 tester	Temperature: 25℃±5℃ Humidity:55%±10%RH
Failure Criteria: Device no longer meets the parts drawing requirements using V+I envelope around REFERENCE I-V curve (pre-zap). (Current tolerance ± 30%; Voltage tolerance ± 30 %)	
Test Voltage: 2000V(+/-);4000V(+/-)	

HUMAN-BODY MODEL TESTING Result

MODEL: HBM		ESD SENSITIVITY PASS: +/-4000V		V CLASS: CLASS 3A
PIN COMBINATION		SAMPLE SIZE	PASSED VOLTS	NOTE:
All other pins to GND(+/-) IO pins to VCC(+/-) IO pins to IO pins (+/-)	2000V	3	+/-2000V	FOR MIL-STD-883H Method 3015.8 CLASS 0 : <250V CLASS 1A: 250V ~< 500V CLASS 1B: 500V -<1000V CLASS 1C: 1000V -<2000V CLASS 2 : 2000V -<4000V CLASS 3A : 4000V-< 8000V CLASS 3B : 8000V~
All other pins to GND(+/-) IO pins to VCC(+/-) IO pins to IO pins (+/-)	4000V	3	+/-4000V	

Pin Assignment

GND: 5
VCC: 8
IO: Other Pins

Remark:
This report refers only to the specimen submitted to testing, and be invalid as separately used.

Testing Engineer:	Approved by:
Waiting Wang	**Sharma**

All other pins to GND(+/-) IO pins to VCC(+/-) IO pins to IO pins (+/-) 2000V (Unit:V)							
Test Pin Fail Voltage	#1	#2	#3	Test Pin Fail Voltage	#1	#2	#3
1	PASS	PASS	PASS	6	PASS	PASS	PASS
2	PASS	PASS	PASS	7	PASS	PASS	PASS
3	PASS	PASS	PASS	8	PASS	PASS	PASS
4	PASS	PASS	PASS				

All other pins to GND(+/-) IO pins to VCC(+/-) IO pins to IO pins (+/-) 4000V (Unit:V)							
Test Pin Fail Voltage	#4	#5	#6	Test Pin Fail Voltage	#4	#5	#6
1	PASS	PASS	PASS	6	PASS	PASS	PASS
2	PASS	PASS	PASS	7	PASS	PASS	PASS
3	PASS	PASS	PASS	8	PASS	PASS	PASS
4	PASS	PASS	PASS				